

# Power consumption: roadblock for AI moving forward

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# Introducing SEL

- Company name: Semiconductor Energy Laboratory Co., Ltd.  
(SEL)
- Location: 398, Hase, Atsugi-shi, Kanagawa, Japan
- Established on July 1, 1980
- Number of employees: 793 (as of April 1, 2017)
- Representative: President Shunpei Yamazaki
- Capital: JPY 4,348,000,000
- Business area: Research and development of transistors, semiconductor devices, and integrated circuits using crystalline oxide semiconductor materials

Flexible OLED display



# Outline

1. What are the roadblocks of AI development?
2. Applying crystalline oxide semiconductors to AI
  - 2-1. DOSRAM (DRAM fabricated with OSFETs)
  - 2-2. Nonvolatile memory, NOSRAM: multi-level memory with no degradation in principle
  - 2-3. Multiply-accumulate operation circuit
  - 2-4. CPU (Noff CPU)
  - 2-5. LSICs with crystalline oxide semiconductor technology
3. Summary

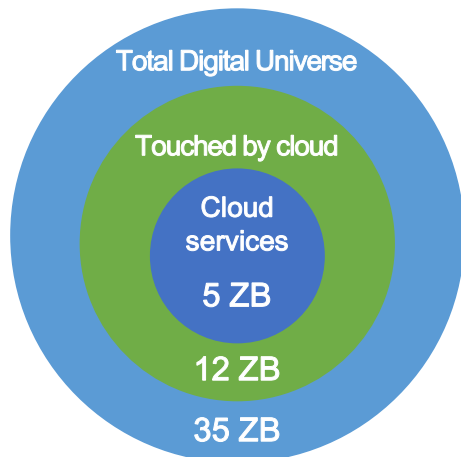
# 1. What are the roadblocks of AI development?

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- 1) Necessity of large-capacity memory
- 2) Latency (software solutions underway)
- 3) Power consumption

# Issues surrounding AI

## 1. Data explosion

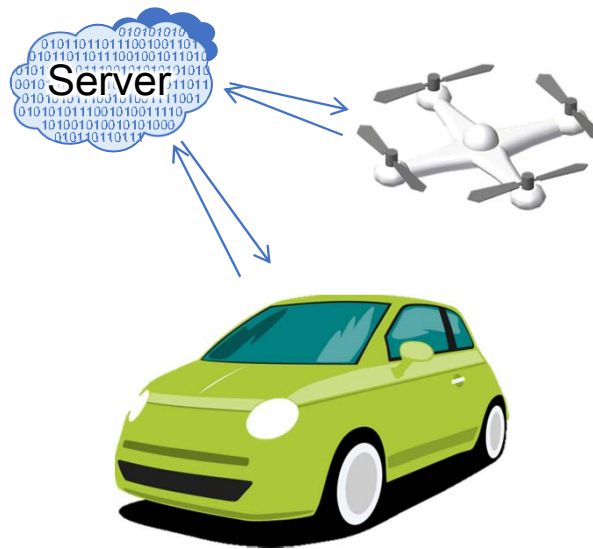


1) IDC "Digital Universe Decade-Are You Ready?"  
<https://www.emc.com/collateral/analyst-reports/idc-digital-universe-are-you-ready.pdf>

\* ZB: zettabyte= $10^{21}$ byte

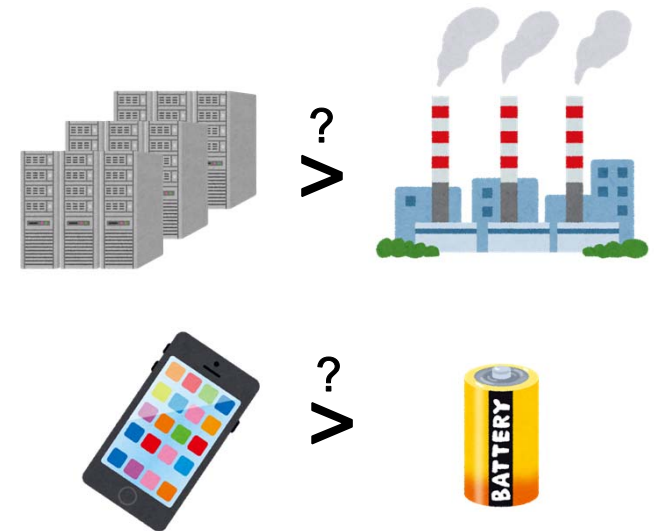
Edge computing necessary as global data use will increase 10x by 2020<sup>1)</sup>

## 2. Latency



Latency unacceptable in self-driving cars and drones

## 3. Power Wall



AI's power consumption impedes edge computing implementation

# Enormous energy consumption in AI development

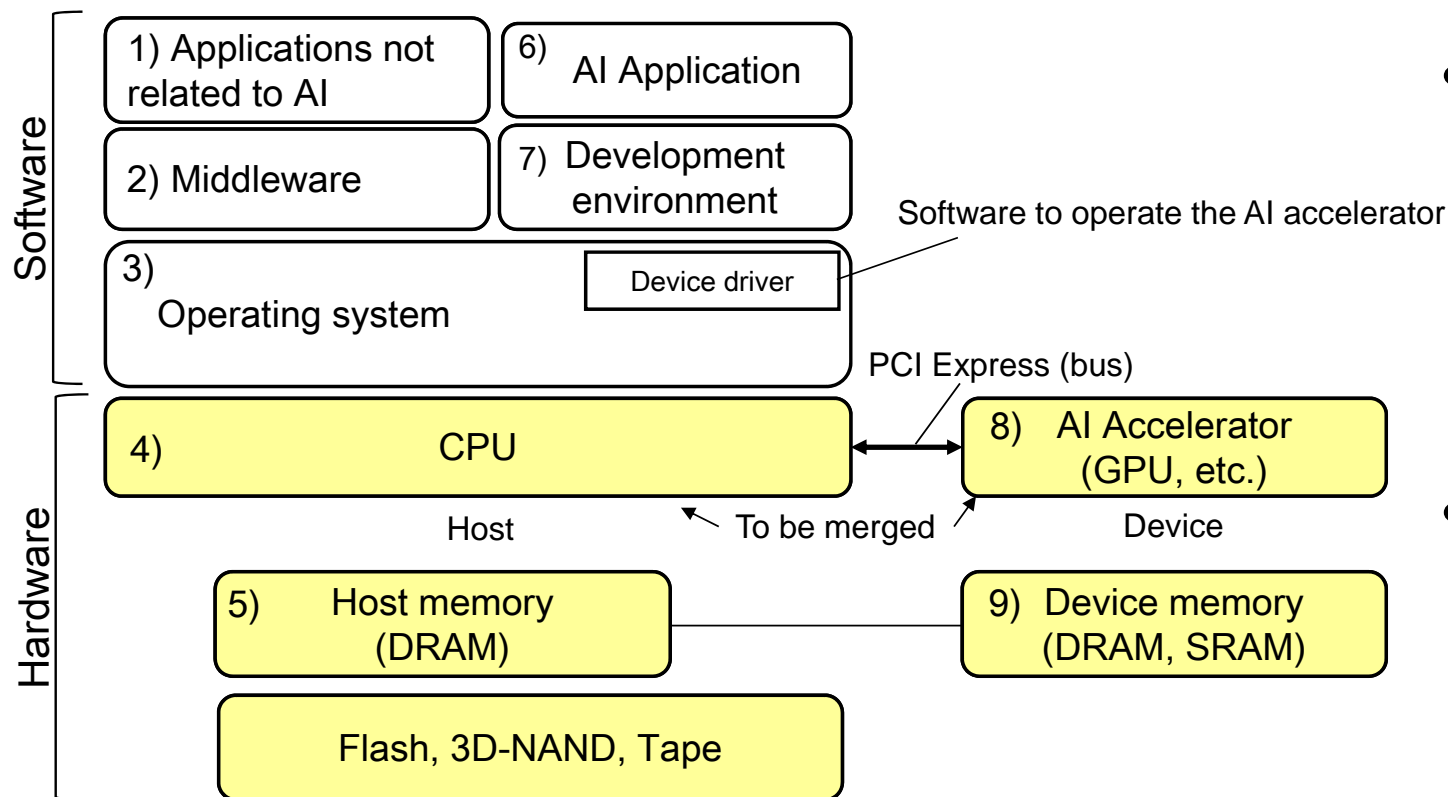
- Korea currently is undertaking a big project to speed up their R&D

*“In order to use actual AI technologies properly in daily lives, experts in related industries say that current amount of electricity consumption needs to be reduced by 1,000 fold.”*

*(From ET News dated Aug. 22, 2017 (<http://english.etnews.com/20170822200001>))*

**Power consumption** of semiconductor devices is the largest factor impeding AI development and extremely low-power AI hardware is needed for future development of AI.

# Hardware/software structure of AI



- AI hardware's total power consumption = AI accelerator + CPU + DRAM, etc...
- Other devices around the accelerator need to run efficiently.

# How do we achieve the power reduction?

- Size and voltage scaling of Si semiconductor devices could, but they have limits
- New technology is needed to reduce the power consumption of AI solutions.

*“In order to reduce amount of electricity consumption, next-generation device technology that can replace CMOS (Complimentary Metal-Oxide Semiconductor) ,which is the foundation of current semiconductor device technology, needs to be developed.”*

*(From ET News dated Aug. 22, 2017 (<http://english.etnews.com/20170822200001>))*

**FETs fabricated with CAAC-IGZO (a crystalline oxide semiconductor material)**

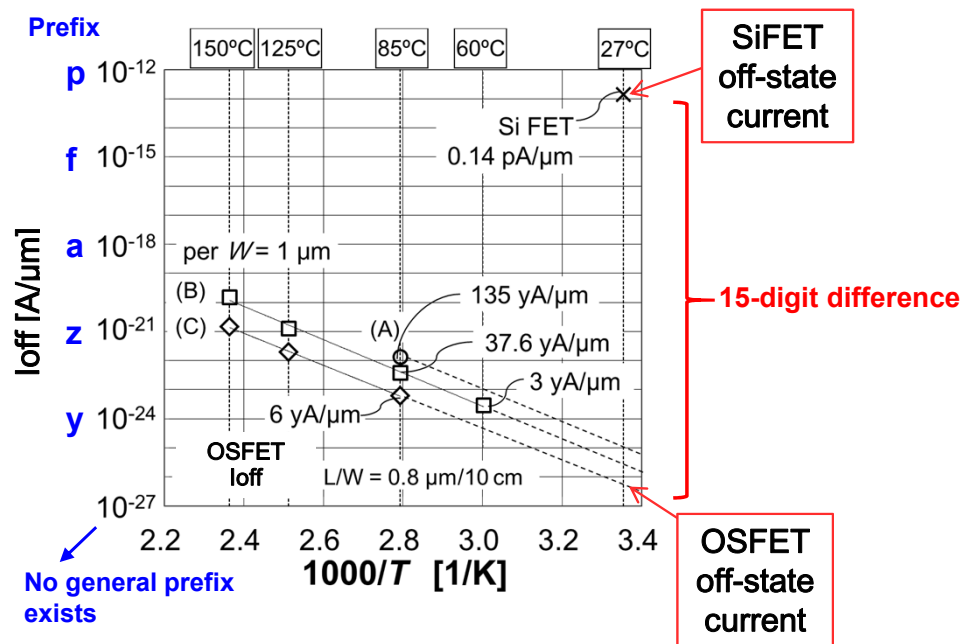
- Off-state current ( $I_{\text{off}}$ ) :  $10^{-24} \text{A}/\mu\text{m}$  (15 digits lower than FETs fabricated with Si,)
- Nonvolatile and high-speed memory devices can be achieved<sup>1)</sup>.

**CAAC-IGZO is the most fitting technology that can challenge Si-CMOS**

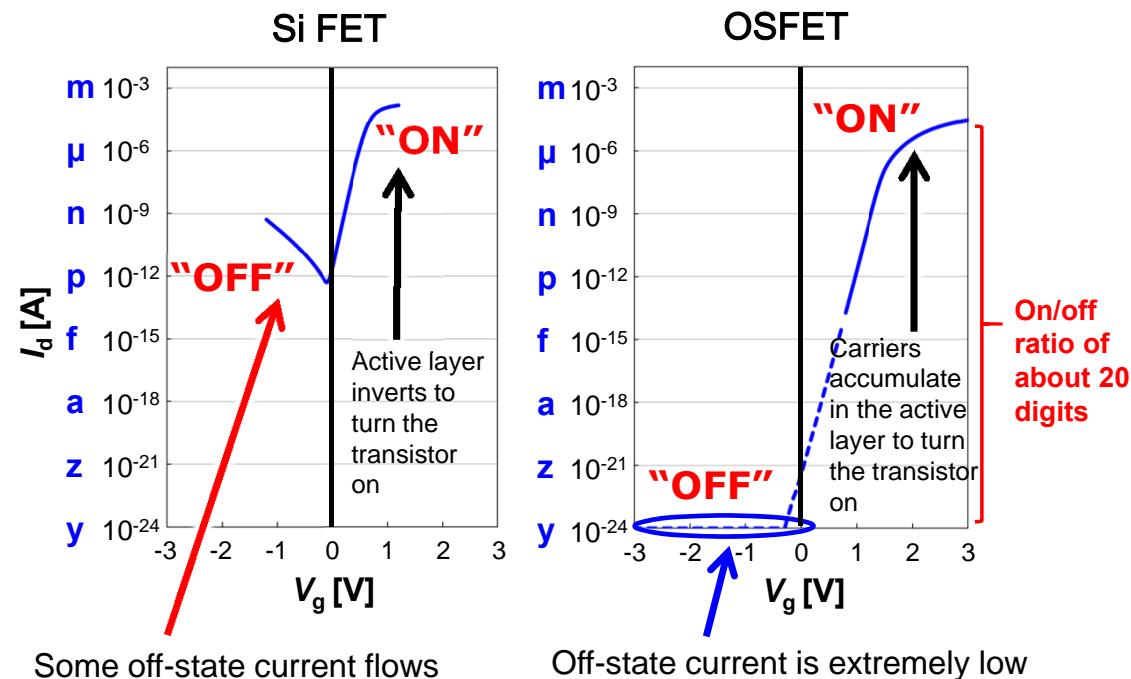


# Extremely low off-state current ( $I_{\text{off}}$ )

- CAAC-IGZO FET has an extremely low  $I_{\text{off}}$  and can drastically reduce the energy consumption of devices.

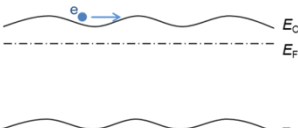
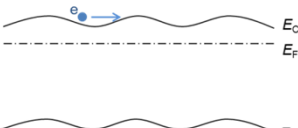
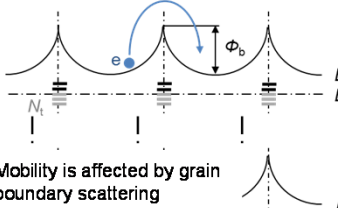
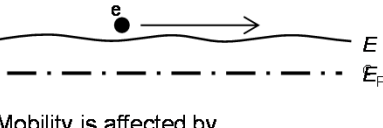
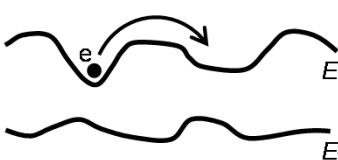
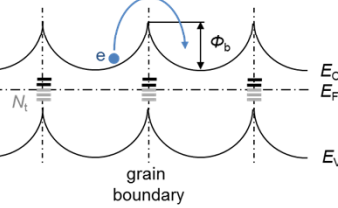
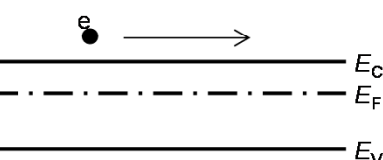


- OSFETs: FETs that use crystalline oxide semiconductors (e.g. CAAC-IGZO)



- (A) K. Kato, *et al.*, Jpn. J. Appl. Phys. 51, (2012) 021201.  
 (B) Reported at FPD International '13  
 (C) H. Tamura, *et al.*, IEEE micro, 34,6, (2014) 42.

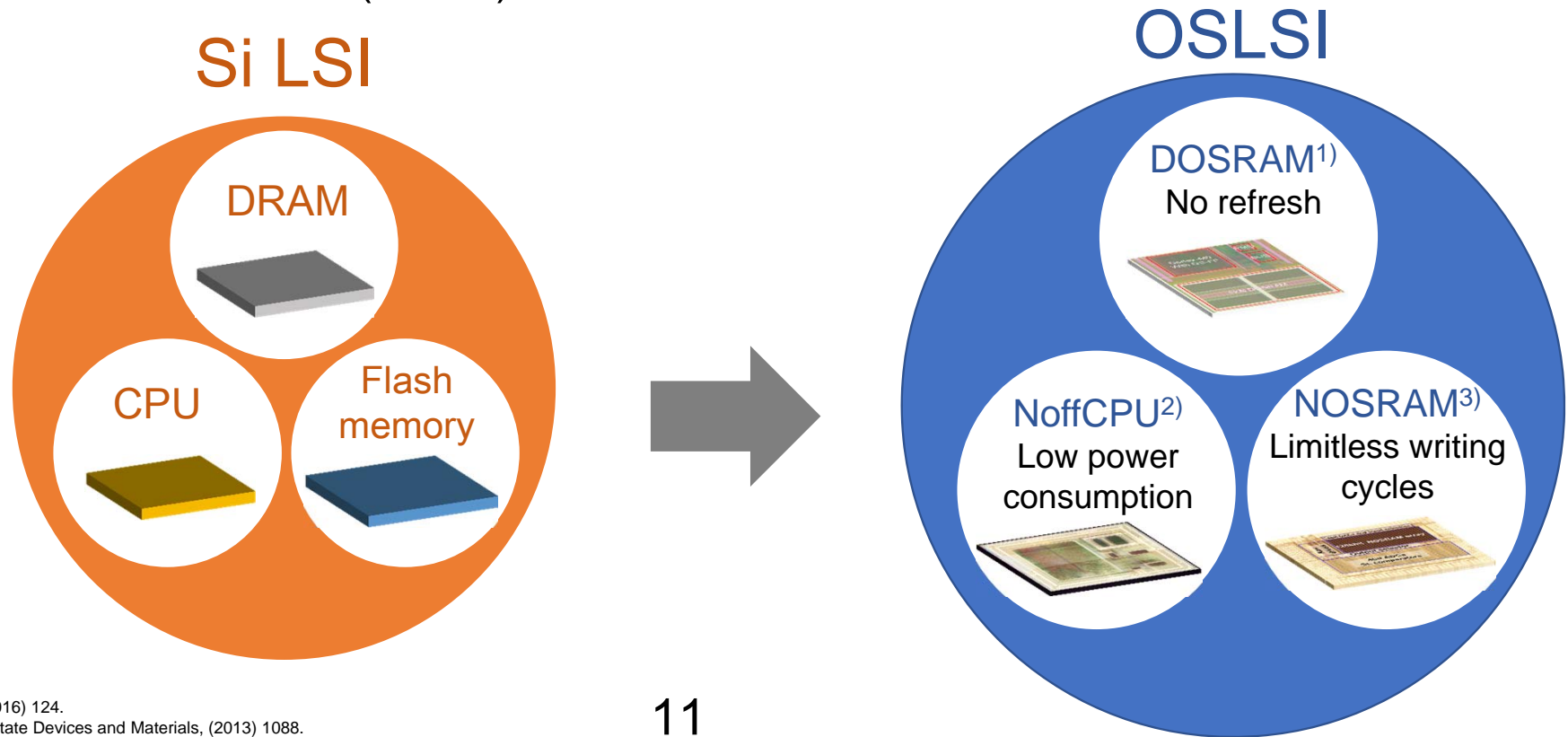
# IGZO's crystal structure and an image of its electrical conduction

	amorphous	CAAC	Poly-crystal	Single crystal
IGZO	<p>a-IGZO is not confirmed by SEL</p>  <p>Mobility is affected by Coulomb scattering the same factor as in single crystal IGZO</p> <p>Hall mobility 4.9 [cm<sup>2</sup>/Vs] (carrier concentration 3.8E+16 cm<sup>-3</sup>)</p> <p>⇒ No effect of grain boundary</p>	<p>CAAC-IGZO</p>  <p>Mobility is affected by Coulomb scattering the same factor as in single crystal IGZO</p> <p>Hall mobility 4.9 [cm<sup>2</sup>/Vs] (carrier concentration 3.8E+16 cm<sup>-3</sup>)</p> <p>⇒ No effect of grain boundary</p>	<p>Poly-IGZO</p>  <p>Mobility is affected by grain boundary scattering</p> <p>Hall mobility 2.9 [cm<sup>2</sup>/Vs] (carrier concentration 2.7E+17 cm<sup>-3</sup>)</p> <p>⇒ Decrease in mobility due to effect of grain boundary</p>	<p>Single crystalline IGZO</p>  <p>Mobility is affected by Coulomb scattering</p>
Si	<p>amorphous Si:H</p>  <p>Mobility is dominated by hopping conduction</p>	<p>CAAC structure is not enabled with Si</p>	<p>Poly-Si</p>  <p>Mobility is dominated by grain boundary scattering</p>	<p>Single crystalline Si</p>  <p>Mobility is dominated by lattice scattering</p>

CAAC is a new crystal structure

# OSLSI is applicable to a variety of hardware

- LSICs using CAAC-IGZO (OSLSI) are applicable to FPGAs, CPUs (NoffCPUs), DRAMs, AI accelerators (GPUs), etc.



1) T. Onuki *et al.*, *Symp. VLSI Circuits*, (2016) 124.

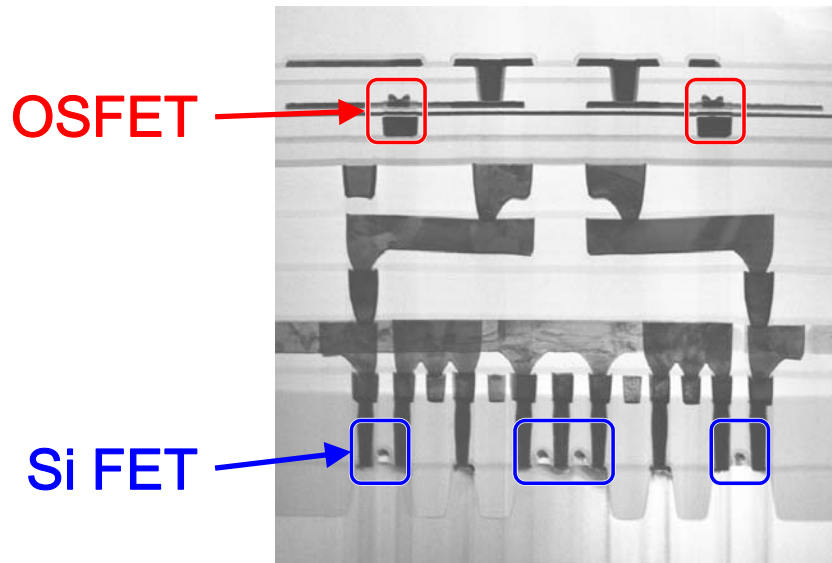
2) Niclas Sjökvist *et al.*, *Ext. Abstr. Solid-State Devices and Materials*, (2013) 1088.

3) T. Matsuzaki *et al.*, *ISSCC Dig. Tech. Pap.*, (2015) 306.

# Hybrid structure of OSLSI chip

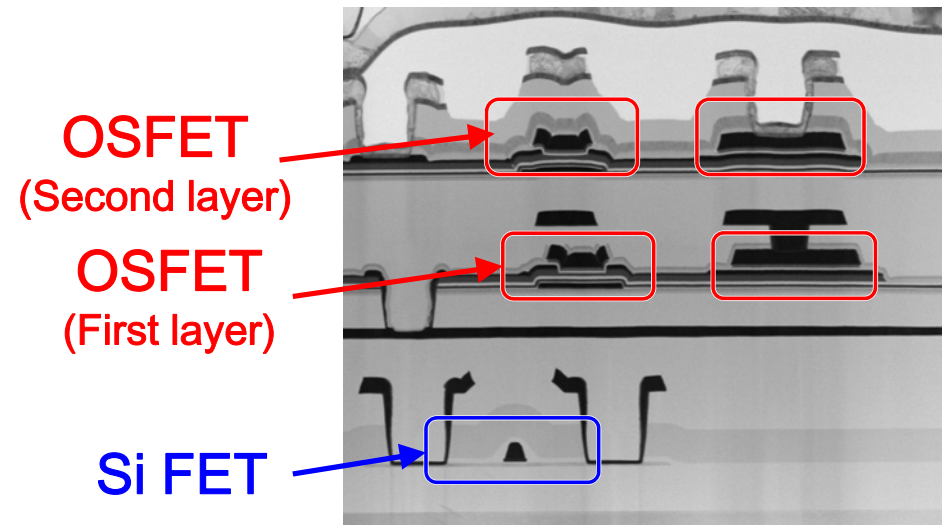
\*voids are filled in the photo.

- Single OSFET layer structure



Cross section of SEL 60nm OS /  
UMC\* 65nm Si

- Multi-layer OSFET



Stack OSFETs  
→higher area efficiency and memory capacity

## 2. Applying crystalline oxide semiconductors to AI

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CAAC-IGZO (c-axis aligned crystalline IGZO)

## 2-1. DOSRAM (DRAM fabricated with OSFETs)

DOSRAM: Dynamic Oxide Semiconductor Random Access Memory

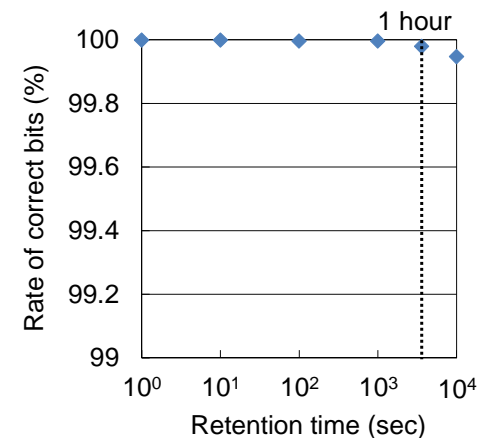
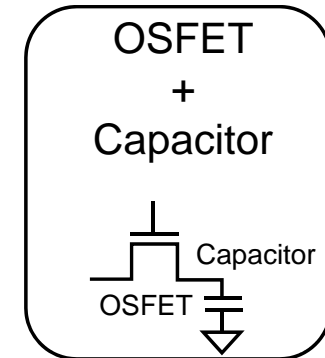
OSFET:      - Extremely low  $I_{off}$  (15 digits lower than Si)  
              - Adequate Ion/frequency characteristics

>10 DRAM chips in 1 AI chip

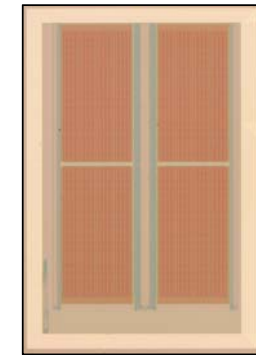
DRAM's refresh period: 60 - 200 ms

DOSRAM's refresh period: 1 h - 1 yr

# Non-volatile DRAM



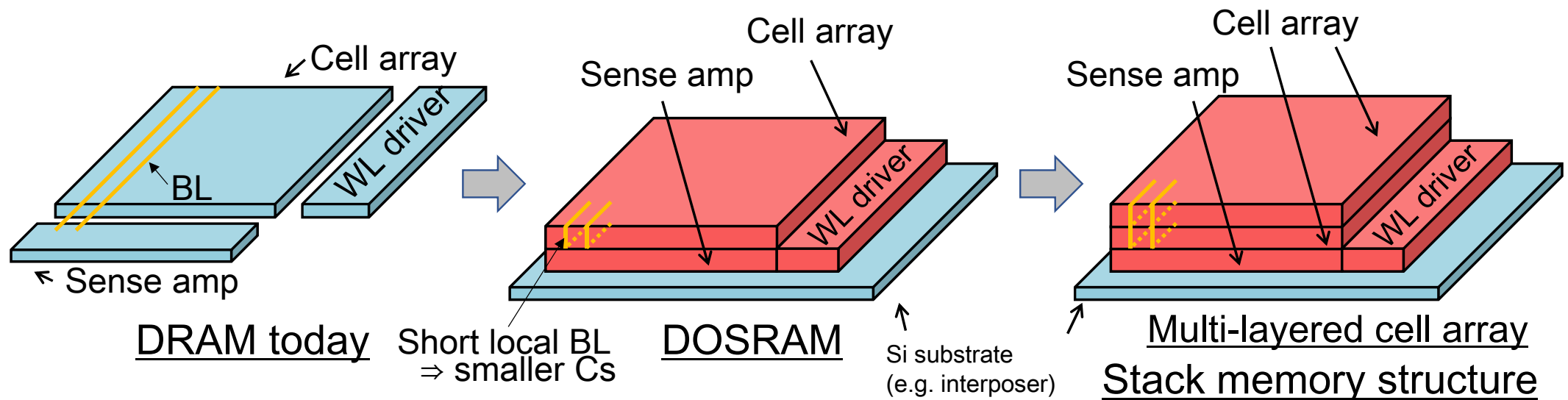
Retention characteristics  
of DOSRAM<sup>1)</sup>



DOSRAM chip  
micrograph<sup>1)</sup>

# OSFET stack (multi-layer) structure of DOSRAM

- OSFET layers (and thus, cell arrays) can be fabricated over other FET layers
  - larger capacity than DRAM
  - smaller  $C_s$  (= lower refresh power)



## 2-2. Nonvolatile memory, NOSRAM<sup>1)</sup>:

Multi-level memory with no degradation in principle

NOSRAM: Nonvolatile Oxide Semiconductor Random Access Memory  
2 transistors, 1 capacitor

- Si flash memory:

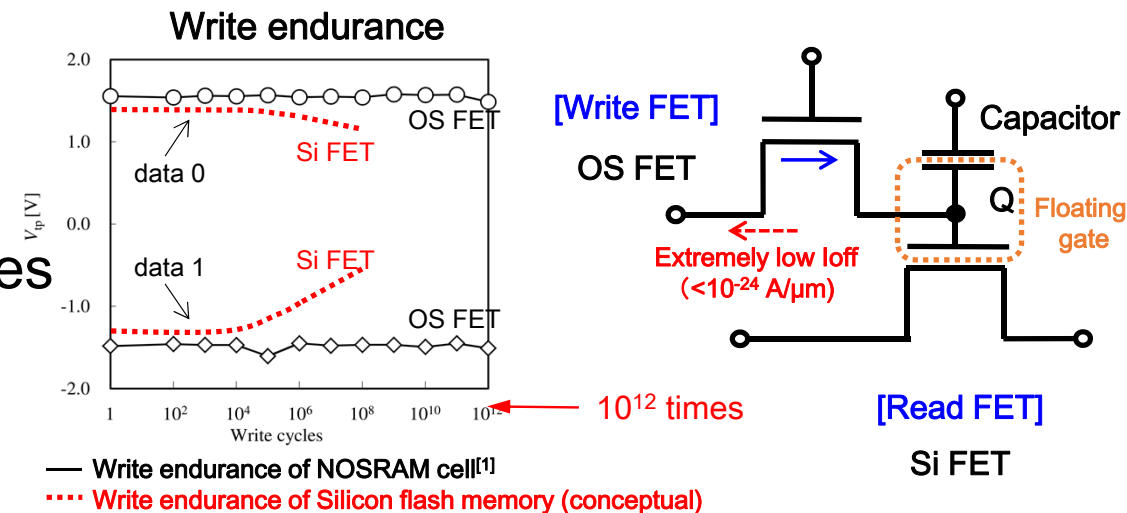
Endures only  $10^4$  to  $10^5$  writes

NOSRAM:

Endures  $> 1,000,000,000,000$  ( $10^{12}$ ) writes

- Si read transistor enables fast writes
- OSFETs can be stacked over SiFETs

NOSRAM develops into a MAC circuit applicable to AI (shown next slide)



<sup>1)</sup> H. Inoue *et al.*, IEEE J. Solid-State Circuits, vol. 47, no. 9, (2012) 2258.



# Application example of NOSRAM to AI operations

NOSRAM cell

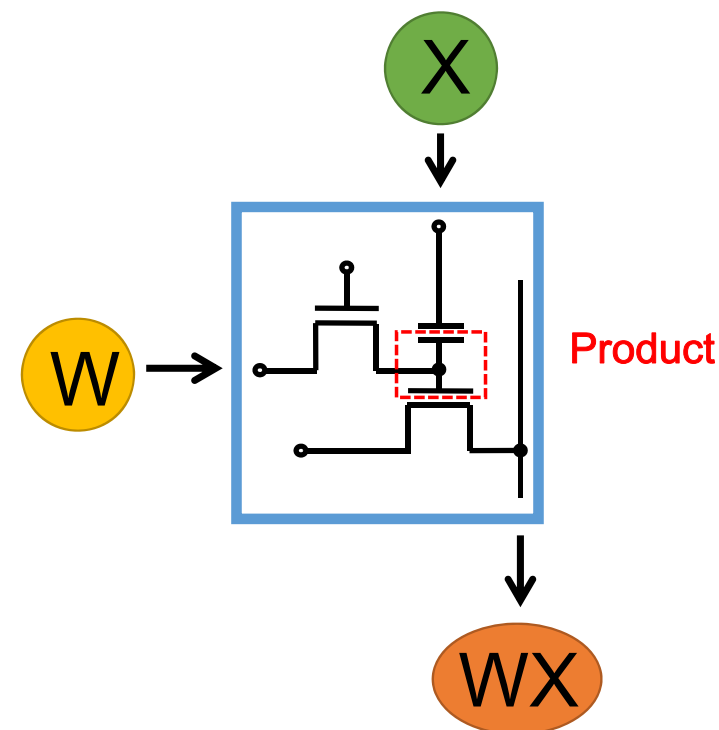
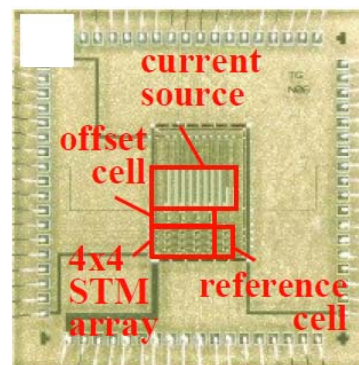
= Applicable to AI operation<sup>1)2)</sup>

NOSRAM cell calculates product  
of X and W



Product sum obtained by simply  
connecting the WX outputs

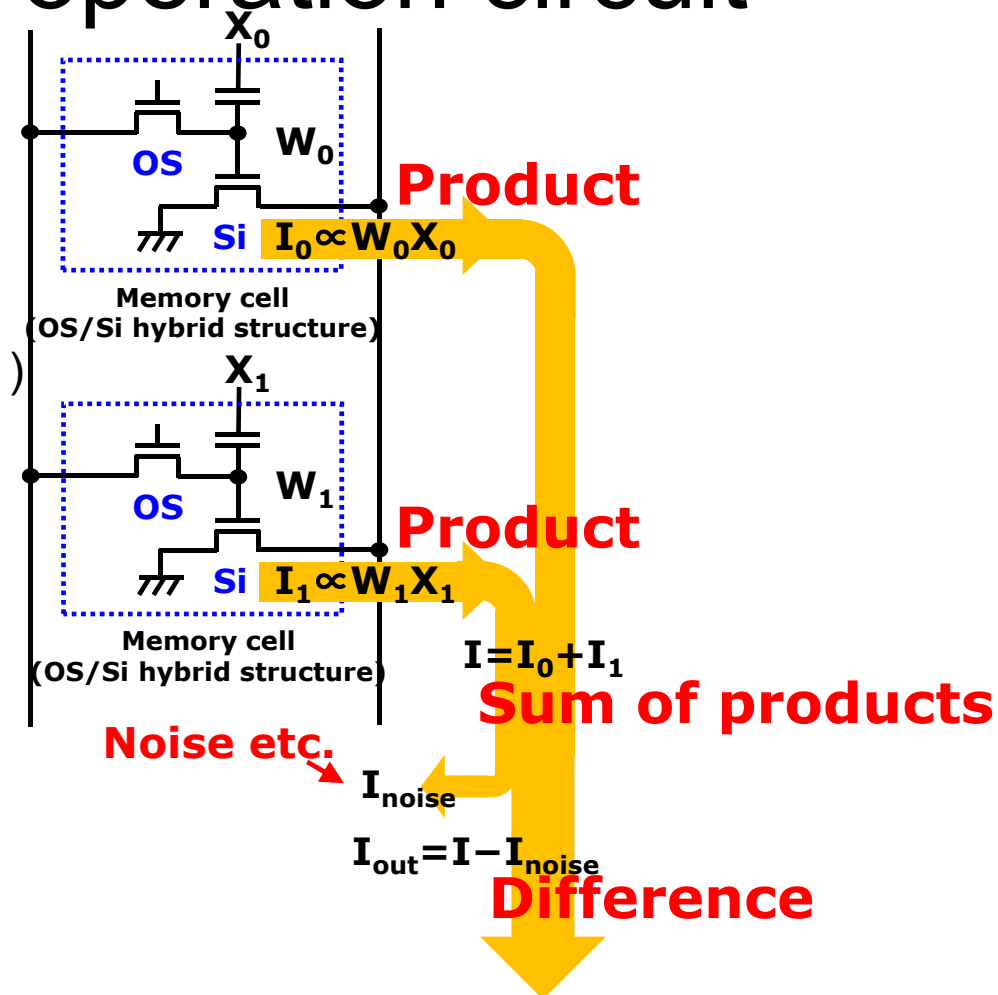
(Details on the next slide)



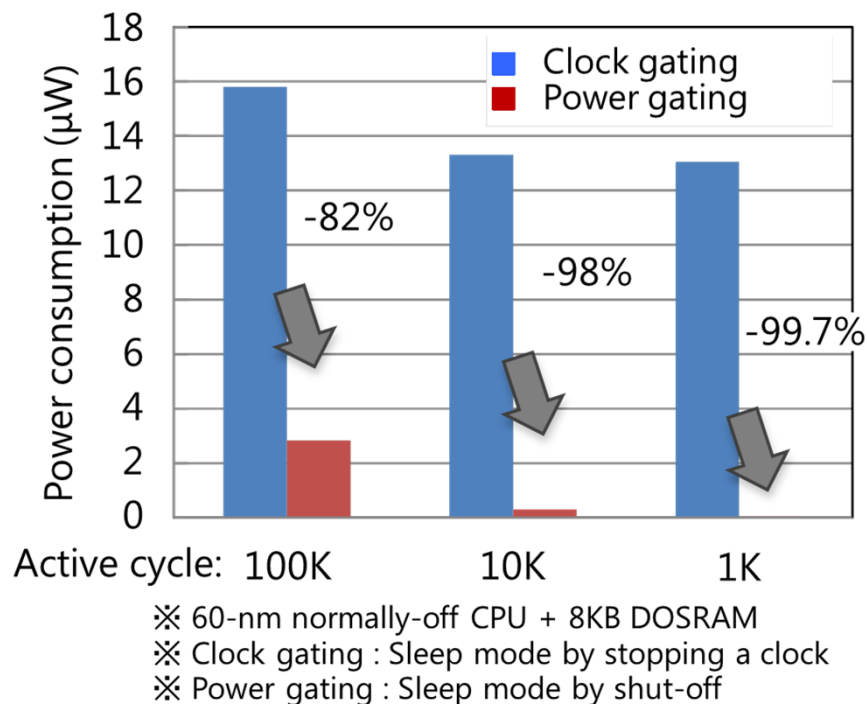
1) Demonstrated at "1<sup>st</sup> AI EXPO", June 28 to 30, 2017, Tokyo Big Sight, Japan  
2) T.Aoki, *et al.*, Ext. Abstr. Solid State Devices and Materials, (2017) 191

## 2-3. Multiply-accumulate operation circuit

- $I_0$  and  $I_1$ : current from memory cells  
 → **Product** ( $W_0 \times X_0, W_1 \times X_1$ )
- Current: current  $I$  (sum of  $I_0$  and  $I_1$ )  
 → **Sum of products** ( $I = I_0 + I_1$ )
- Subtract noise etc. from current  $I$   
 Current  $I_{out}$  ( $I_{out} = I - I_{noise}$ )  
 → **Difference**
- Operation accuracy can be improved with difference operation and multiply-accumulate operation.

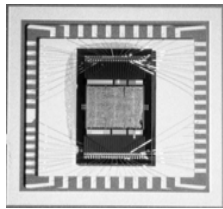


## 2-4. Example of CPU with OSLSI (NoffCPU)

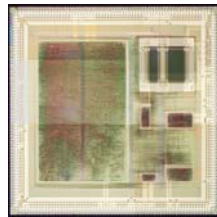


**1000x** CPU standby power reduction

## 2-5. LSICs with crystalline oxide semiconductor technology (OSLSI)



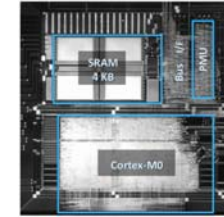
(1) 8bit Noff\* CPU  
SSDM 2012



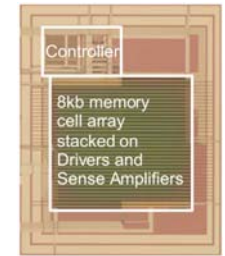
(2) 32bit Noff CPU  
SSDM 2013



(3) FPGA  
ISSCC 2014



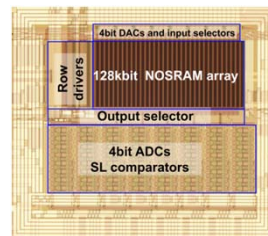
(4) Cortex-M0 with SRAM  
Cool Chips 2014



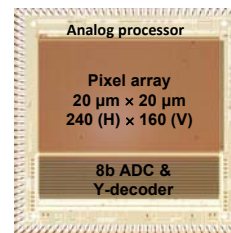
(5) DOSRAM  
IMW 2012



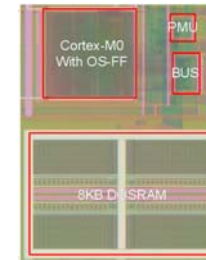
(6) 1Mbit NOSRAM  
JSSC 2012



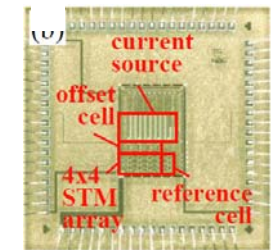
(7) 4bit/cell NOSRAM  
ISSCC 2015



(8) Image Sensor  
ISSCC 2015



(9) DOSRAM  
VLSI 2016



(10) STM  
SSDM 2017

\*Noff: normally off

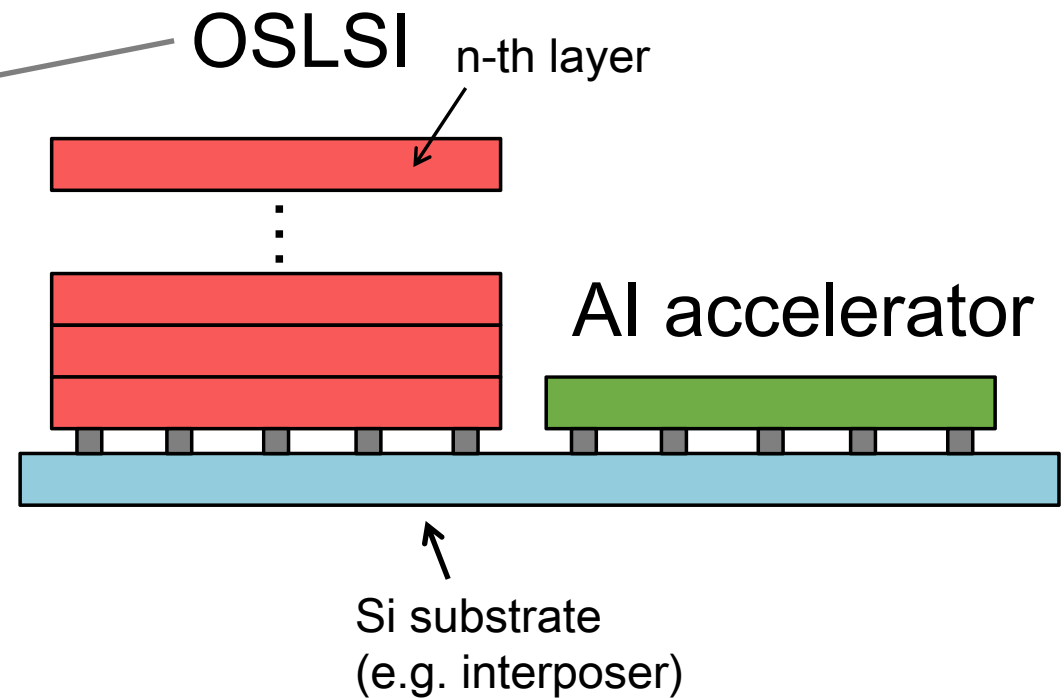
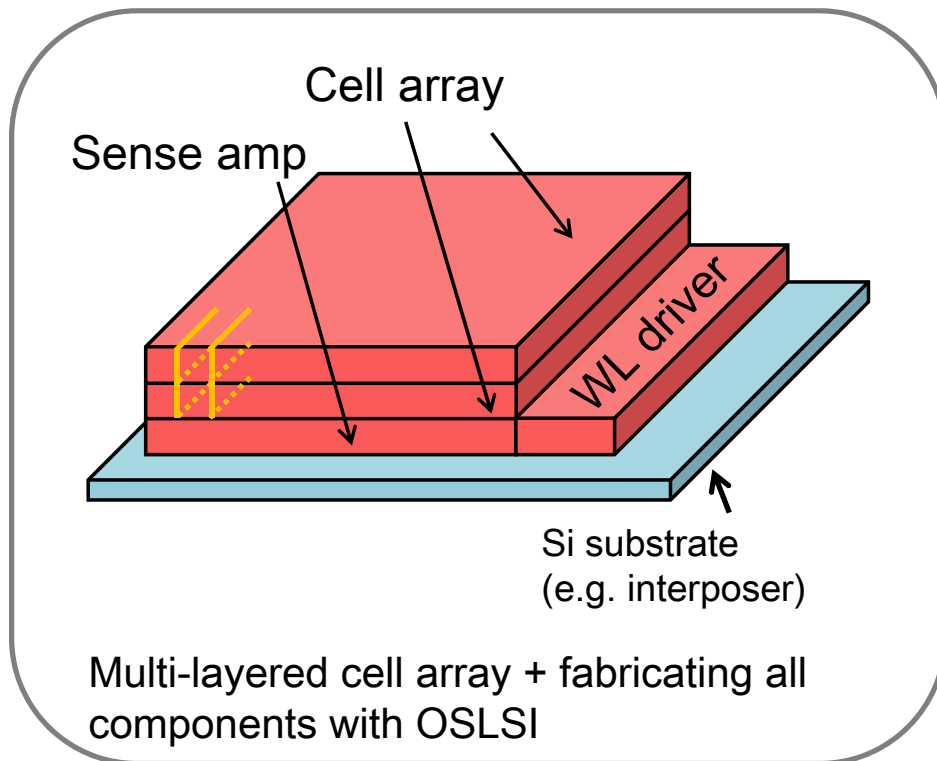
- (1) T. Ohmaru *et al.*, Ext. Abstr. Solid-State Devices and Materials, (2012) 1144.  
 (2) Niclas Sjkqvist *et al.*, Ext. Abstr. Solid-State Devices and Materials, (2013) 1088.  
 (3) T. Aoki, *et al.*, ISSCC Dig. Tech. Pap., (2014) 502.  
 (4) H. Tamura *et al.*, COOL Chips XVII, (2014).  
 (5) T. Atsumi *et al.*, 4th IEEE Int. Memory Workshop, (2012) 99.

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- (6) H. Inoue *et al.*, IEEE J. Solid-State Circuits 47, (2012) 2258.  
 (7) T. Matsuzaki *et al.*, ISSCC Dig. Tech. Pap., (2015) 306.  
 (8) T. Ohmaru *et al.*, ISSCC Dig. Tech. Pap., (2015) 118.  
 (9) T. Onuki *et al.*, Symp. VLSI Circuits, (2016) 124.  
 (10) T. Aoki, *et al.*, Ext. Abstr. Solid State Devices and Materials, (2017) 191.

# AI-OSLSI Stack LSI structure

## Example of OSLSI



### 3. Summary

- (1) All AI hardware run on Si circuits now
  - (2) Crystalline oxide semiconductor materials (e.g., CAAC-IGZO) enable low-power semiconductor devices  
→ next-generation semiconductor material
  - (3) Crystalline oxide semiconductor material is the only material with such a low off-state current
  - (4) OSLSI challenges SiLSI technology
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Thank you!

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